

Search Notes

Application/Control No.

10/500,540

Examiner

Sargon N. Nano

Applicant(s)/Patent under
Reexamination

RYUKAWA ET AL.

Art Unit

2157

SEARCHED

Class	Subclass	Date	Examiner
709	208, 212 227	2/2/2007	SN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (see attached report)	2/2/2007	SN